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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/674,402	01/02/2001	P.S. Ramanujam	MBHB00-1120	8359	
20306	7590 07/10/2006		EXAMINER CHU, KIM KWOK		
	ELL BOEHNEN HULBE	RT & BERGHOFF LLP			
300 S. WACKER DRIVE					
32ND FLOO	R		ART UNIT	PAPER NUMBER	
CHICAGO,	IL 60606		2627		
			DATE MAILED: 07/10/200	6	

Please find below and/or attached an Office communication concerning this application or proceeding.

		Amaliaa	4! NI -	A 12 4/- 1				
			tion No.	Applicant(s)	Applicant(s)			
	055 - 4 - 4' 0	09/674,	402	RAMANUJAM ET	RAMANUJAM ET AL.			
Office Action Summary		Examin	er	Art Unit				
		Kim-Kwa		2627				
Period fo	The MAILING DATE of this communi or Reply	cation appears on t	he cover sheet wit	th the correspondence a	ddress			
WHIC - Exte after - If NC - Failu Any	ORTENED STATUTORY PERIOD FO CHEVER IS LONGER, FROM THE MA Insions of time may be available under the provisions of SIX (6) MONTHS from the mailing date of this common operiod for reply is specified above, the maximum star re to reply within the set or extended period for reply verify received by the Office later than three months af ed patent term adjustment. See 37 CFR 1.704(b).	AILING DATE OF Tof 37 CFR 1.136(a). In no curication. tutory period will apply and will, by statute, cause the a	THIS COMMUNIC event, however, may a re will expire SIX (6) MONT pplication to become ABA	ATION. ply be timely filed "HS from the mailing date of this ANDONED (35 U.S.C. § 133).	•			
Status	,							
1)[\inf	Responsive to communication(s) filed	d on Amendment fi	led on June 9 20	06				
2a)□	•	b)⊠ This action is		<u>oo</u> .				
3)	Since this application is in condition f	<i>′</i> —		ers prosecution as to th	e merits is			
٠,۵	closed in accordance with the practic	•		•				
Dispositi	on of Claims	, , , , , , , , , , , , , , , , , , , ,	,	.,				
·		the application						
-	l) Claim(s) 11 and 16 is/are pending in the application.							
	4a) Of the above claim(s) is/are withdrawn from consideration.							
· · ·	Claim(s) is/are allowed.							
·	Claim(s) <u>11 and 16</u> is/are rejected.							
7)	Claim(s) is/are objected to.	ion and/or clockion						
8)[Claim(s) are subject to restrict	ion and/or election	requirement.	•				
Applicati	on Papers							
9)[The specification is objected to by the	Examiner.						
10)🛛	The drawing(s) filed on <u>10/31/2000</u> is	/are: a)⊠ accepte	d or b)□ objected	d to by the Examiner.				
	Applicant may not request that any object	tion to the drawing(s)	be held in abeyand	ce. See 37 CFR 1.85(a).				
	Replacement drawing sheet(s) including	the correction is requ	ired if the drawing(s	s) is objected to. See 37 C	FR 1.121(d).			
11)	The oath or declaration is objected to	by the Examiner. N	Note the attached	Office Action or form P	TO-152.			
Priority ι	ınder 35 U.S.C. § 119							
12)🛛	Acknowledgment is made of a claim for	or foreign priority u	nder 35 U.S.C. §	119(a)-(d) or (f).				
	☑ All b)☐ Some * c)☐ None of:		•	,,,,,				
·	1. Certified copies of the priority of	documents have be	en received.					
	2. Certified copies of the priority of			plication No. PCT/HU9	9/00035.			
	3. Copies of the certified copies of		•	·				
	application from the Internation	•			· ·			
* 8	See the attached detailed Office action	for a list of the cer	tified copies not r	eceived.				
Attachmen	t(s)							
	e of References Cited (PTO-892)		4) Interview Su		•			
_	e of Draftsperson's Patent Drawing Review (PT nation Disclosure Statement(s) (PTO-1449 or F			/Mail Date formal Patent Application (PT	O-152)			
	r No(s)/Mail Date	,	6) Other:		 ,			

Response to Remarks

1. Applicant's Amendment filed on June 09, 2006 has been fully considered.

The objected claim 11 with allowable subject matters is rejected because a newly found art of Chen (US Patent 5,257,133) and Tanaka (US Patent 5, 684,641). Chen discloses an aspherical objective lens and Tanaka discloses an aspherical objective lens made of plastics.

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. § 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claims 11 and 16 are rejected under 35 U.S.C. 103 (a) as being unpatentable over Faruqi et al. (WO 97/02563) in view of Chen (U.S. Patent 5,257,133) and Tanaka et al. (U.S. Patent 5,684,641).

Faruqi teaches an apparatus for the writing and reading of a holographic recording medium very similar to that of the present invention. For example, Faruqi teaches the following:

- (a) as in claim 11, the recording medium 25 is an optical card (Fig. 7; page 17, lines 8-10);
- (b) as in claim 11, a recording medium 25 holding an/or positioning mechanism 30 (Figs. 4 and 5); page 15, lines 9 and 10);
- (c) as in claim 11, movable or fixed read and write optics
 16-24 (Fig. 4);

- (d) as in claim 11, the write optics 16 comprising a polarized writing light source (Figs. 4 and 15; laser 1 is inherently a polarized light source and its light beam is further polarized by modulator 73); page 21, lines 13-15);
- (e) as in claim 11, polarizing selector means 57 for separating an/or combining the reference beam and an object beam (Figs. 4 and 11; page 21, lines 27-31);
- (f) as in claim 11, an object beam modulating means 24
 (Fig. 4);
 - (q) as in claim 11, a polarization wave plate 56 (Fig. 11);
- (h) as in claim 11, an objective lens 58 for imaging the object beam onto a recording layer (Fig. 18; page 21, last line, page 22, lines 1 and 2);
- (i) as in claim 11, the read optics 17, 24 comprising a polarized reading light source 17 (Figs. 4 and 15);
- (j) as in claim 11, the read optics includes a polarizing selector 57 and/or spatial filtering means 39, 42 for separating and/or combining a reference beam and an image beam (Figs. 6 and 11);
- (k) as in claim 11, a light detector 44, 45 and an objective lens 58 for imaging the image beam onto the light detector (Figs. 4, 6 and 11);

- (1) as in claim 11, the wavelength of the reading light source 17 is different from the writing light source 16 (Fig. 4; page 11, lines 23-25);
- (m) as in claim 11, the read optics 17 comprise wavelength distortion correcting means 24, 27 for correcting the distortion of the reconstructed image caused by the difference in the wavelength of the reading and writing light (Figs. 4 and 11; signal processor 27 and optical head 24 reconstruct the stored image without error);
- (n) as in claim 16, the read optics and the write optics have a common objective lens (Fig. 4; in optical head 24);
- (o) as in claim 16, the common objective lens 58 is for the correction of the wavelength distortion (Fig. 4; optical head 24 reconstruct the stored image without error);
- (p) as in claim 16, the objective lens 58 (in 24) has a central region and an annular region in its aperture (Fig. 4; inherent feature of an objective lens having a focusing region consists of a central region surrounded by an annular region);
- (q) as in claim 16, the central region is tuned (utilized) to the wavelength of the writing light source 16 for focusing the write object beam onto the recording layer (Fig. 4);
- (r) as in claim 16, the central region is tuned (utilized) the wavelength of the read light source 17 for imaging the read object beam onto the detector (Fig. 4); and

(s) as in claim 16, the annular region of the lens is tuned (utilized) to the wavelength of the read light source 17 for imaging the reflected object beam onto the detector (Fig. 4; the inherent objective lens with an outside region surrounding the inside region is used for focusing the write and read light beams).

However, Faruqi does not teach the following:

(a) as in claims 11 and 16, the wavelength distortion (chromatic or spherical aberration) correcting means is an aspherical plastic objective lens.

Chen teaches the following:

(a) a chromatic aberration caused by difference in wavelengths can be corrected by an aspherical objective lens (claim 4, column 7, lines 61-63).

Tanaka teaches the following:

(a) the aspherical objective lens is made of plastic(column 6, claim 3).

A focused light beam has an aberration affected by its wavelengths spectrum. In order to correct this kind of focusing distortion, it would have been obvious to one of ordinary skill in the art to replace Chen's aspherical objective lens with Faruqi's optical lens 58 to focus the write and read light beams, because Chen's aspherical lens compensate the chromatic and spherical aberrations of the focused light beams.

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Furthermore, although both Faruqi and Chen do not disclose their objective lens are made of plastics, for a more cost effective optical head, it would have been obvious to one of ordinary skill in the art to replace the material of Chen's silicon aspherical lens with Tanaka's plastic aspherical lens, because a plastic lens is cheaper to make and lighter in weight than a silicon lens.

4. Any inquiry concerning this communication or earlier communication from the examiner should be directed to Kim CHU whose telephone number is (571) 272-7585 between 9:30 am to 6:00 pm, Monday to Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, William Korzuch, can be reached on (57) 272-7589.

The fax number is:

(571) 273-8300 (for formal communications intended for entry. Or:

(571) 273-7585, (for informal or draft communications, please label "PROPOSED" or "DRAFT").

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished application is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov.

Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9191 (toll free).

THANG V. TRAN

Kim-Kwok CHU

Examiner AU2627 June 29, 2006

le 6/29/06

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